

# New requirements of IEC 61000-4-4 Edition 3 - 2012

## Trends for next revision of IEC 61000-4-5



Eric Dudenhoeffer, TESEQ AG, Switzerland  
*Product Line Manager*

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**TESEQ**  
Advanced Test Solutions for EMC

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

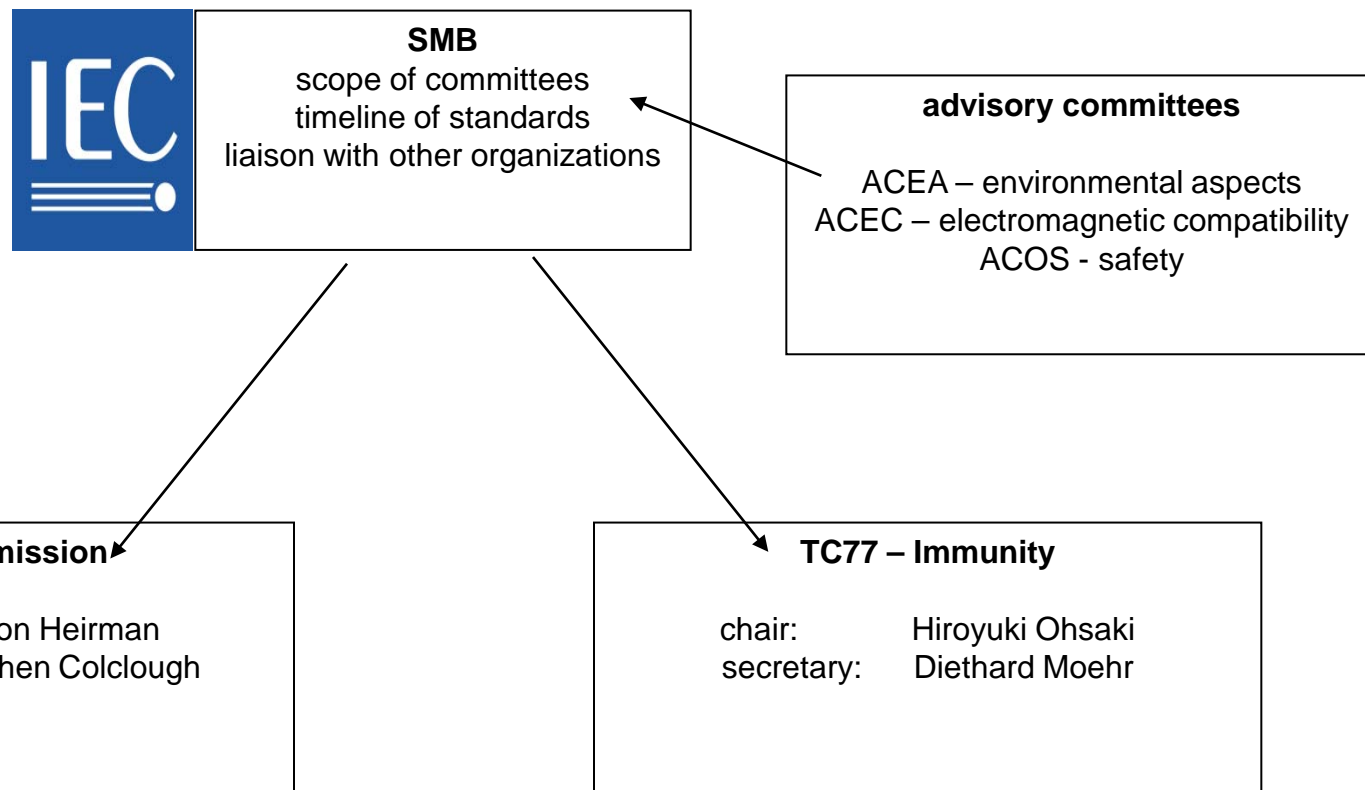


 **SCHAFFNER**  
Test Systems

Became

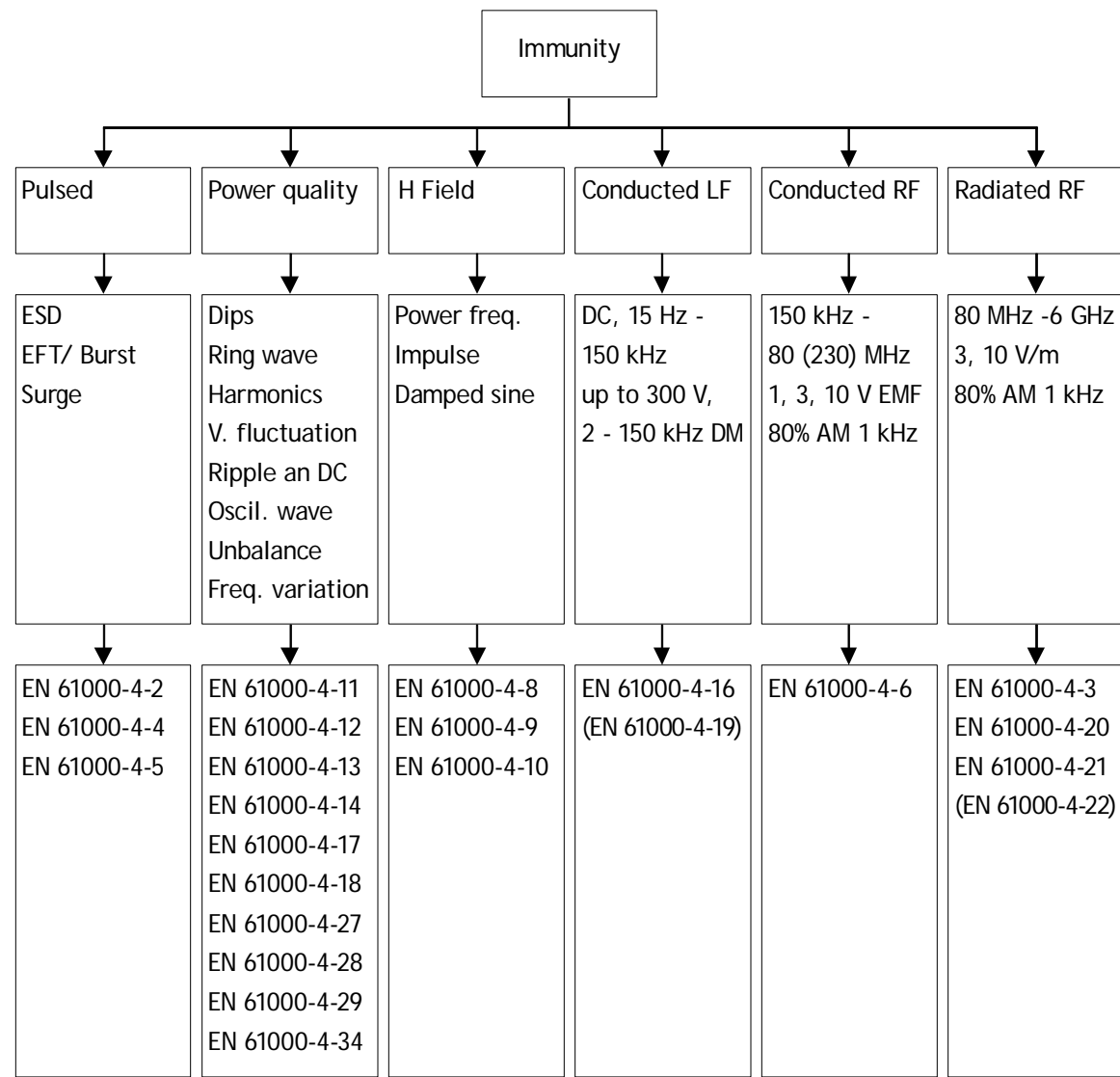
**T E S E T** 

Advanced Test Solutions for EMC



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

# Immunity standards



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$



## IEC 61000-x-x basic standards

- Terminology and safety
- Description of phenomena and levels
- Guidance values for immunity tests
- Measurement techniques
- Testing techniques
- Installation guidelines

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$



## Generic standards

- Residential, commercial and light industry
  - Houses, shops and supermarkets
  - Business premises
  - Areas of public entertainment
  - Outdoor locations, petrol stations, sport centres
  - Light industrial locations, workshops and laboratories
  
- Industrial environment
  - Locations with industrial, scientific and medical apparatus
  - Heavy inductive or capacitive loads frequently switched
  - High currents and associated magnetic field



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$



## Product standards

### Particular products

- Washing machines
- Electricity meters
- Monitors
- Printed boards

### Product families

- LV household equipment
- Information technology equipment
- Medical equipment

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$



| Publication | Year | Edition | Maintenance | Responsibility |
|-------------|------|---------|-------------|----------------|
| 61000-4-2   | 2008 | Ed. 2.0 | 2014        | MT12           |
| 61000-4-3   | 2010 | Ed. 3.2 | 2013        | WG10           |
| 61000-4-4   | 2011 | Ed. 2.1 | 2012        | MT12           |
| 61000-4-5   | 2005 | Ed. 2.0 | 2012        | MT12           |
| 61000-4-6   | 2008 | Ed. 3.0 | 2013        | WG10           |
| 61000-4-9   | 2001 | Ed. 1.1 | 2013        | MT12           |
| 61000-4-10  | 2001 | Ed. 1.1 | 2013        | MT12           |
| 61000-4-12  | 2006 | Ed. 2.0 | 2012        | MT12           |
| 61000-4-18  | 2011 | Ed. 1.1 | 2012        | MT12           |
| 61000-4-20  | 2010 | Ed. 2.0 | 2014        | JTF TEM        |
| 61000-4-21  | 2011 | Ed. 1.0 | 2015        | JTF REV        |
| 61000-4-22  | 2010 | Ed. 1.0 |             | JTF FAR        |



# $s(q_k) = \sqrt[n]{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^n}$ Electrical Fast Transients - Burst



EFT

Electrical Fast Transient

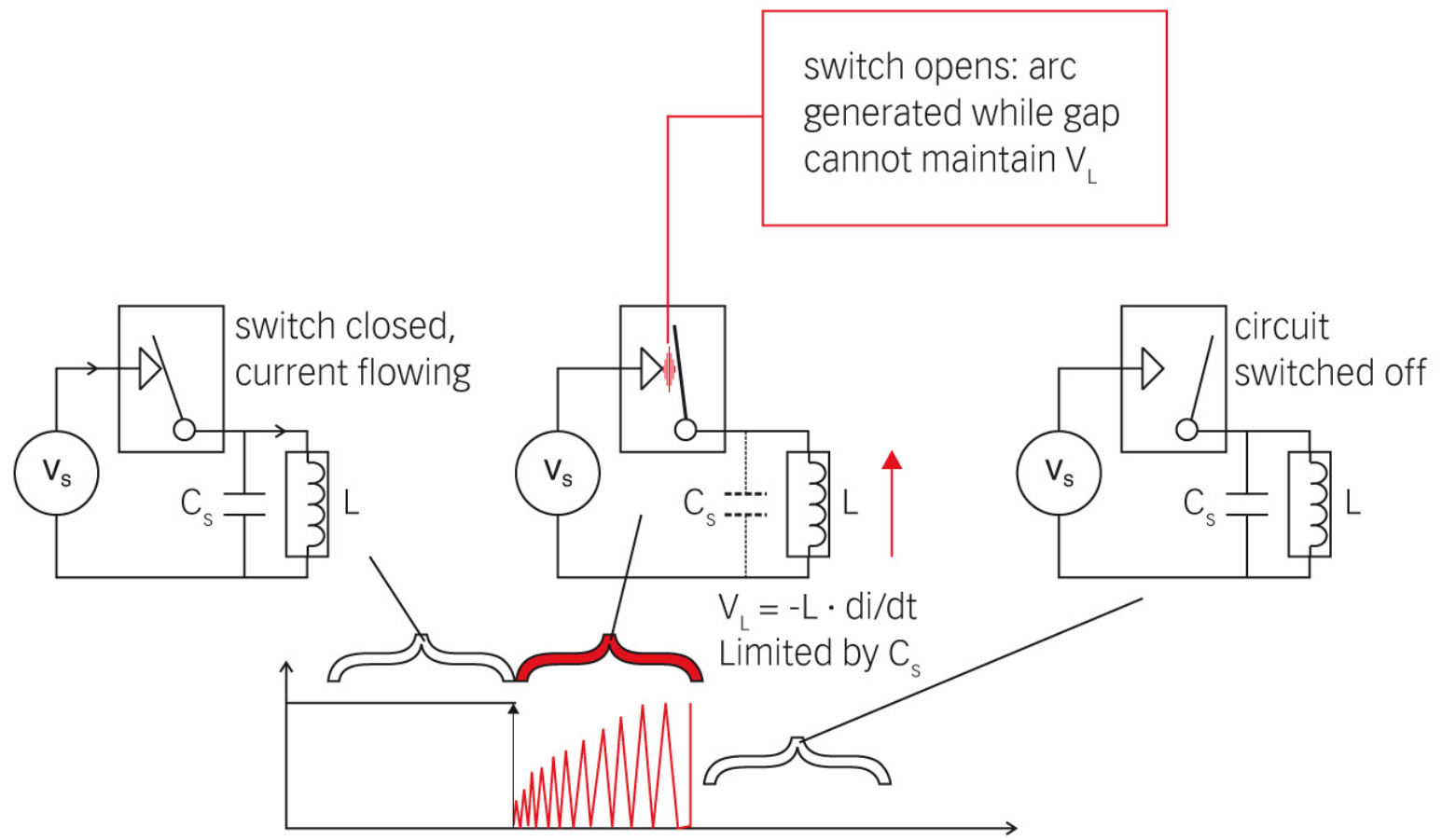
Burst Pulses

$$s(q_k) = \sqrt[n]{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# EFT/Burst – IEC/EN 61000-4-4



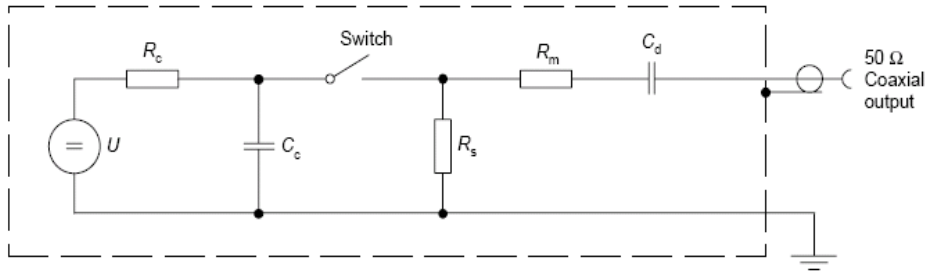
EF  
IE



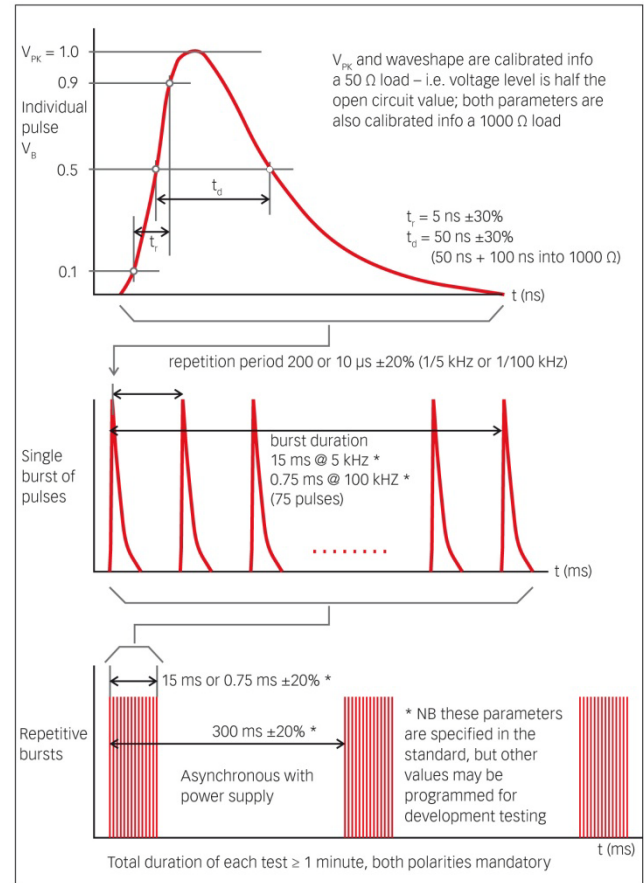


$$s(q_k) = \sqrt[n]{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# IEC 61000-4-4: Electromagnetic compatibility (EMC) - Part 4-4 : Testing and measurement techniques - Electrical fast transient/burst immunity test - Basic EMC Publication



EFT / Burst is a high frequency phenomenon with a bandwidth > 100 MHz



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

## Burst : IEC 61000-4-4



- New publication of IEC 61000-4-4:Ed 3.0 (May 2012)

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

## Maintenance of IEC 61000-4-4



- Started Dec 2008
- Result inquiry within MT12 and observations from national committees defined the program.

### No change of:

- Test levels
- Generator specifications
- Test repetition frequency

### Change (review) of:

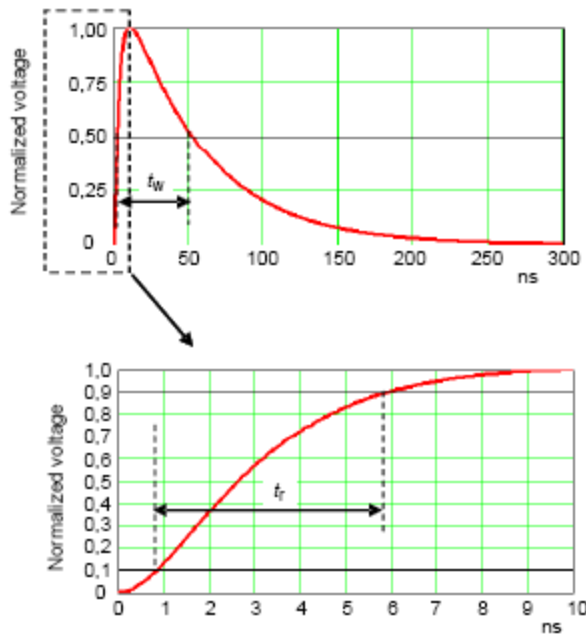
- Test setup (i.e. rack mount, table top, AE wiring)
- Calibration of clamp
- Taking Amdt 1:2010 to main body
- Numerical model of a Burst pulse
- Measurement Uncertainty

$$s(q_k) = \sqrt[n]{\frac{1}{n-1} (q_k - Q)}$$

# Model of a Burst Pulse



- Informative: for Engineering and Design purposes



The formula of the ideal waveform of Figure 3,  $v_{EFT}(t)$ , is as follows:

$$v_{EFT}(t) = k_v \left[ \frac{v_1}{k_{EFT}} \cdot \frac{\left(\frac{t}{\tau_1}\right)^{n_{EFT}}}{1 + \left(\frac{t}{\tau_1}\right)^{n_{EFT}}} \cdot e^{-\frac{t}{\tau_2}} \right]$$

where

$$k_{EFT} = e^{-\frac{\tau_1}{\tau_2} \left(\frac{n_{EFT} \cdot \tau_2}{\tau_1}\right)^{\frac{1}{n_{EFT}}}}$$

and

$k_v$  is maximum or peak value of the open-circuit voltage ( $k_v = 1$  means normalized voltage)

$$v_1 = 0,92 \quad \tau_1 = 3,5 \text{ ns} \quad \tau_2 = 51 \text{ ns} \quad n_{EFT} = 1,8$$

NOTE The origin of this formula is given in IEC 62305-1:2010, Annex B.

Figure 3 – Ideal waveform of a single pulse into a 50 Ω load with nominal parameters  $t_r = 5 \text{ ns}$  and  $t_w = 50 \text{ ns}$



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Test Setups



For EUTs with cable inputs on the top

- This method is difficult to meet
- This has been investigated
- Numerical simulations have been made for alternative setups
- Measurement campaigns have been run
- An easier alternative has been found, validated and will be published in Ed 3.0

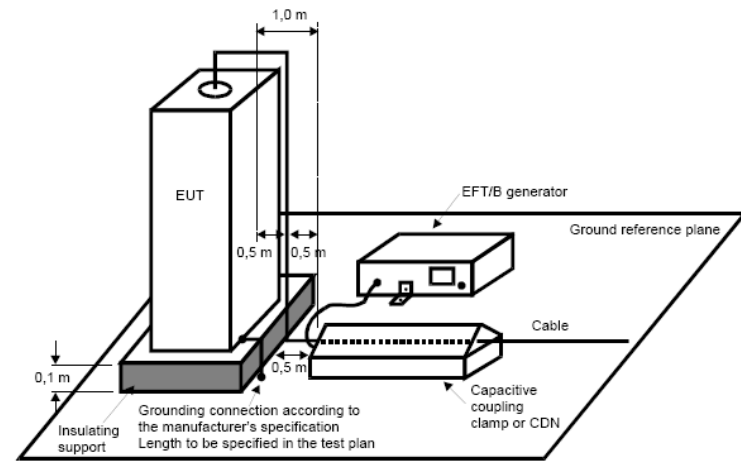
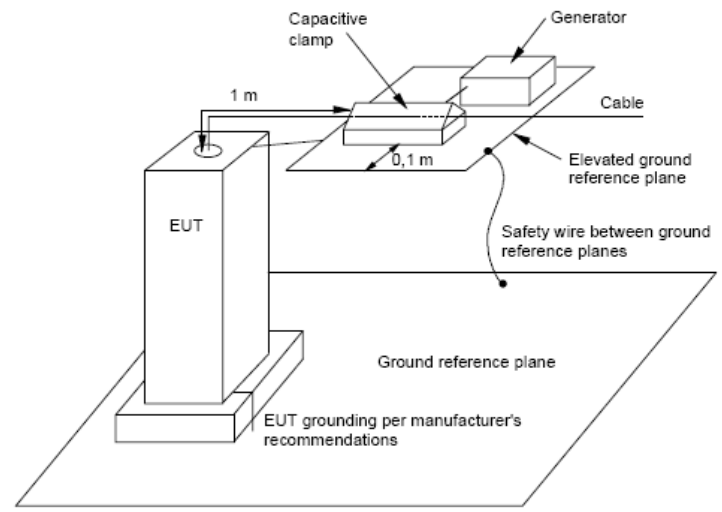


Figure 13 – Example of a test setup for equipment with elevated cable entries

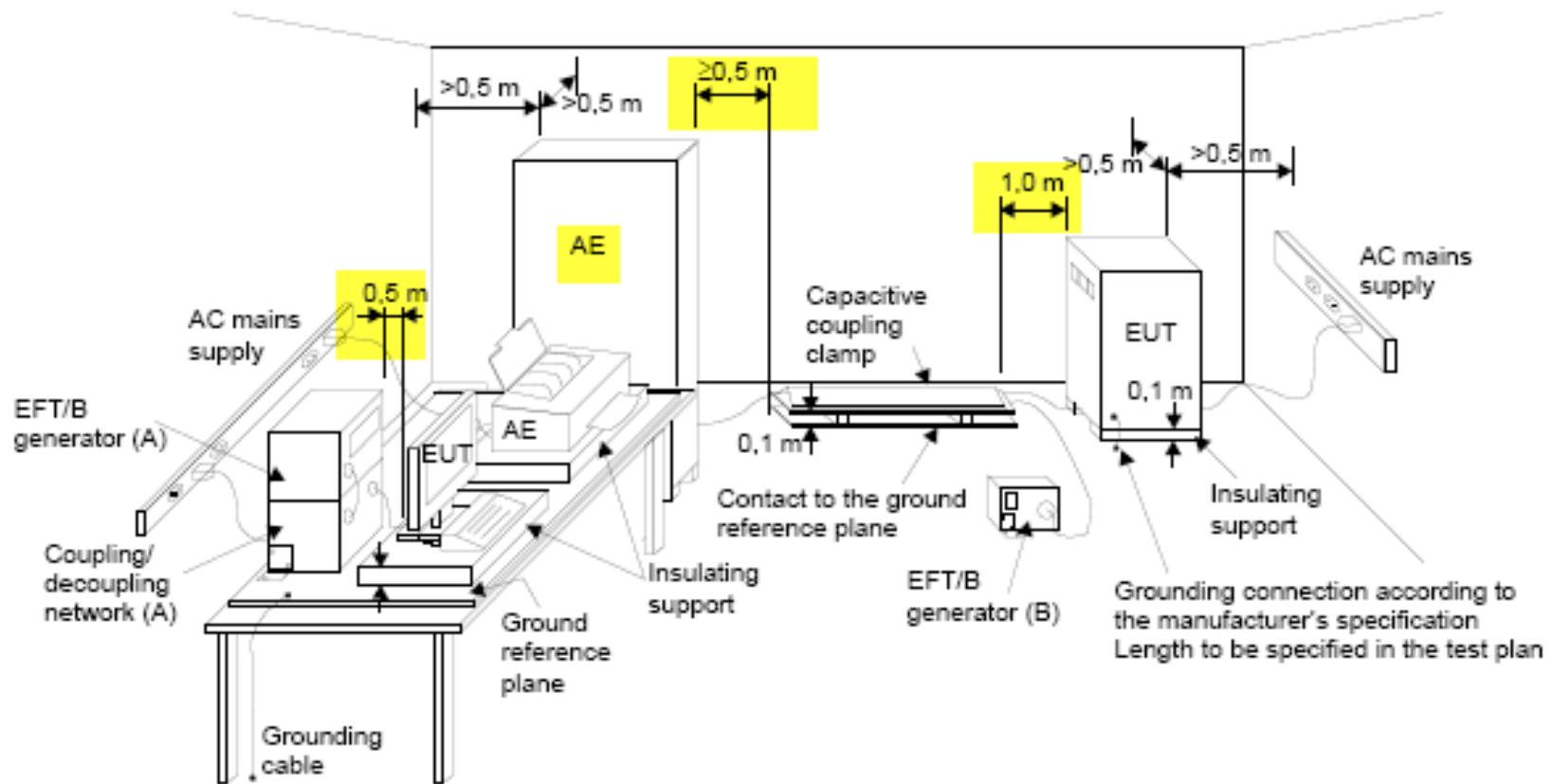
$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

# Other Changes in Test Setups



- Some of the changes are shown in yellow:

61000-4-4/FDIS © IEC



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n q_k^2}$$

# Calibration of Coupling Clamp



Various methods have been proposed and investigated

- Using network analysers
- Using RLC bridges
- Using same equipment (attenuators and scope) as for generator calibration

Finally the best method has been selected:

- Using same equipment (attenuators and scope) as for generator calibration



$$s(q_k) = \sqrt{\frac{1}{n-1}}$$

# Calibration of Coupling Clamp

- IEEE publication about the new method

## Full-wave Investigation of EFT Injection Clamp Calibration Setup

**Spartaco Caniggia**  
EMC Consultant  
Viale Moranti 7,  
20010 Bareggio (MI), Italy  
[spartaco.caniggia@ieee.org](mailto:spartaco.caniggia@ieee.org)

**Eric Dudenhoeffen**  
TESEQ AG  
Nordstrasse 11F, CH-4542 Luterbach  
Switzerland  
[eric.dudenhoeffen@teseq.com](mailto:eric.dudenhoeffen@teseq.com)

**Francesca Romana Maradei**  
Dept. of Electrical Eng.,  
Sapienza Univ. of Rome  
Via Eudossiana 18, 00184 Rome, Italy  
[fr.maradei@ieee.org](mailto:fr.maradei@ieee.org)

The validity of the method has been investigated through numerical simulations and validated by a measurement campaign.

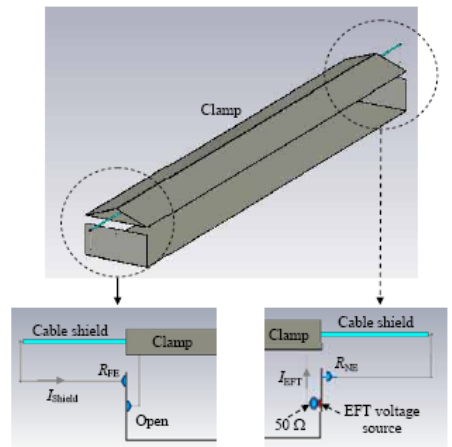


Fig. 3 – MWS model of capacitive coupling clamp housing a coaxial cable.

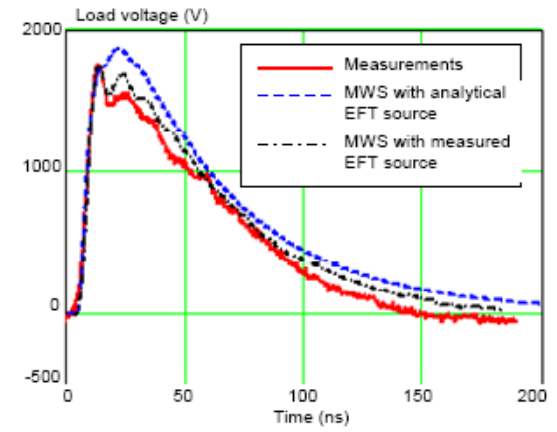


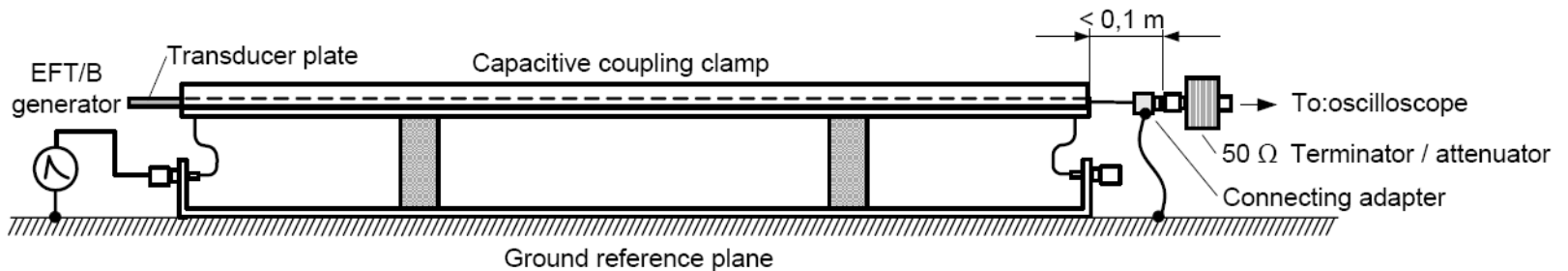
Fig. 15 – Load voltage obtained by measurements and MWS model in calibration setup configuration [2].

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

# Calibration of Coupling Clamp



- Need of a transducer plate and adapter



**Figure 8 – Calibration of a capacitive coupling clamp using the transducer plate**

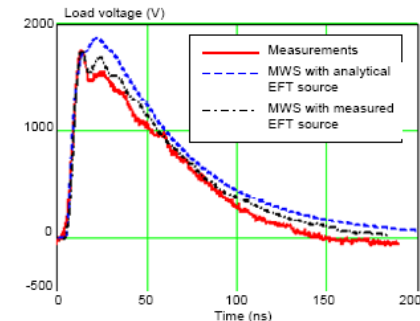
The waveform shall be calibrated with a single 50 Ω termination.

The clamp shall be calibrated with a generator, which has been shown to be compliant with the requirements of 6.2.2 and 6.2.3.

The calibration is performed with the generator output voltage set to 2 kV.

The waveform characteristics shall meet the following requirements:

- rise time ( $5 \pm 1,5$ ) ns;
- pulse width ( $50 \pm 15$ ) ns;
- peak voltage ( $1\ 000 \pm 200$ ) V.



**Fig. 15 – Load voltage obtained by measurements and MWS model in calibration setup configuration [2].**

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Generator Calibration



- IEC 61000-4-4 Amdt 1:2010 has been taken in the main body of Ed 3.0

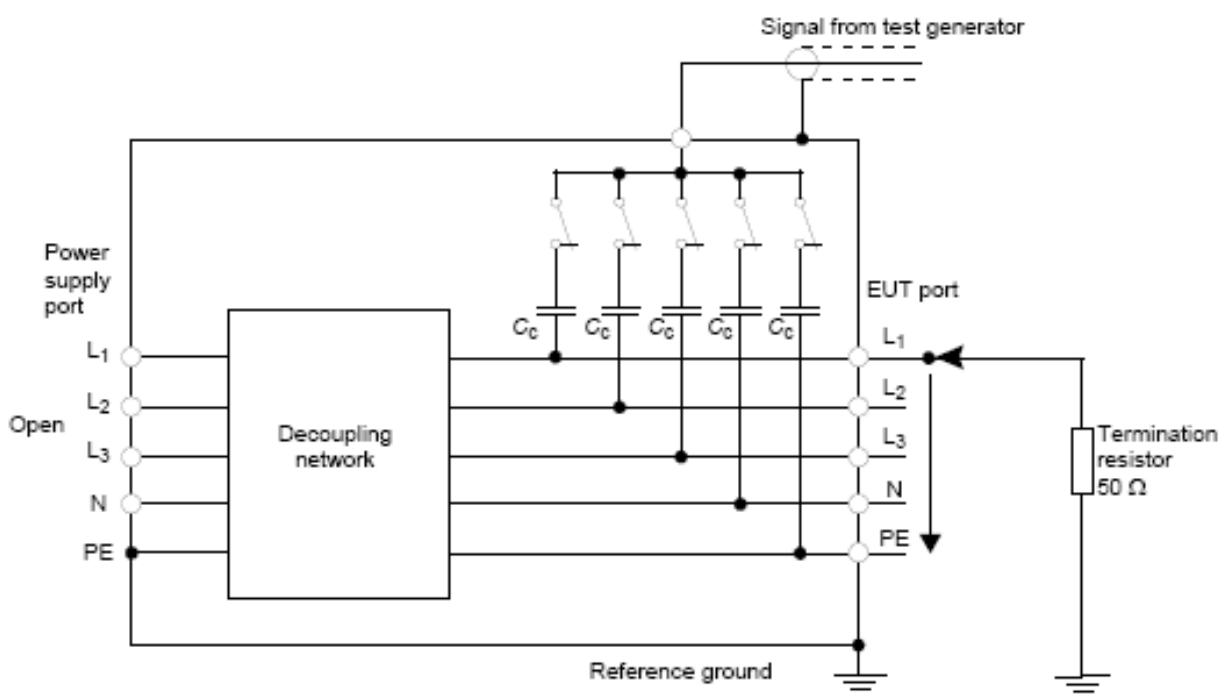


Figure 5 – Calibration of the waveform at the output of the coupling/decoupling network

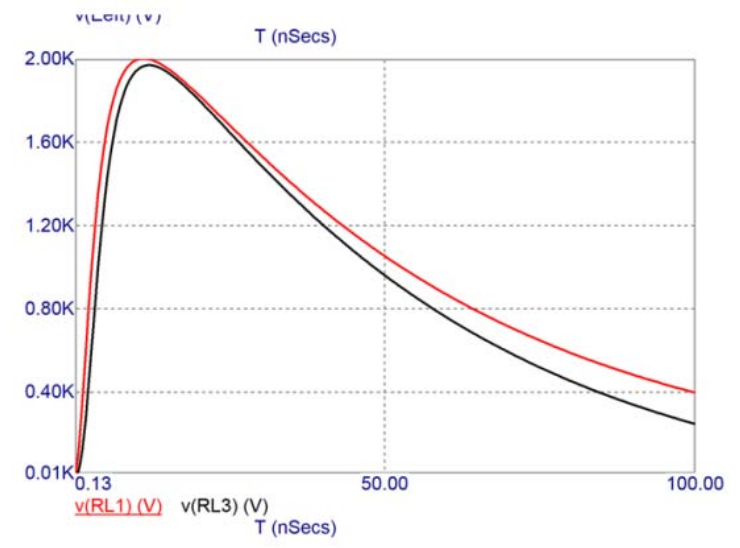


$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Generator Calibration



- The introduction of Measurement Uncertainty considerations pushed to look at things closer
- The use of numerical simulation tools allowed better visibility
- The introduction of the Amdt 1:2010 calibration method generates results drifts which were neglected



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Generator Calibration



- To make things right, specifications have been re-adjusted for parameter values when measured with new method (full common mode) at CDN output
- Note that there is no change for generator or CDN specification, the new calibration method generates slight changes in the parameter definition at CDN output
- Using the new definition from Ed 3.0 for calibration will give results which are better centered in the tolerance range

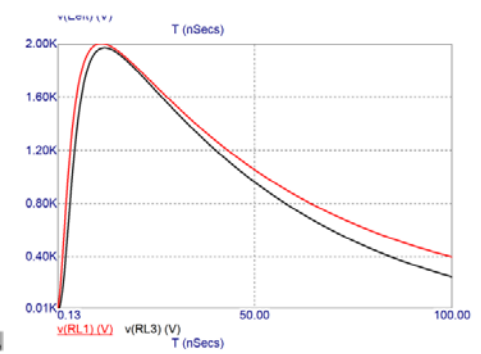
The calibration is performed with the generator output at a set voltage of 4 kV. The generator is connected to the input of the coupling/decoupling network. Each individual output of the CDN (normally connected to the EUT) is terminated in sequence with a 50 Ω load while the other outputs are open. The peak voltage and waveform are recorded for each polarity.

Rise time of the pulses shall be  $(5,5 \pm 1,5)$  ns.

Pulse width shall be  $(45 \pm 15)$  ns.

Peak voltage shall be  $(2 \pm 0,2)$  kV, according to Table 2.

NOTE 2 The values shown above are the result of the calibration method of the CDN



# Annex C: Measurement Uncertainty (MU) Considerations



- Informative (not mandatory)
- Will be implemented in each new immunity standard
- Is in line with IEC 61000-1-6

Title:

IEC/TR 61000-1-8 Ed.1: ELECTROMAGNETIC COMPATIBILITY (EMC) – Part 1-8: General – Guide to the assessment of measurement uncertainty

- Concerns only the test equipment calibration uncertainty, not the uncertainty of the burst test
- Dedicated to the calibration laboratories
- Ends with an important statement about compliance of test equipment:

## **C.5 Application of uncertainties in the EFT/B generator compliance criterion**

Generally, in order to be sure the generator is within its specifications, the calibration results should be within the specified limits of this standard (tolerances are not reduced by MU).

$$s(q_k) = \frac{1}{\sqrt{1 - n}} (q_k - Q)$$

## Lightning transients – SURGE – IEC 61000-4-5

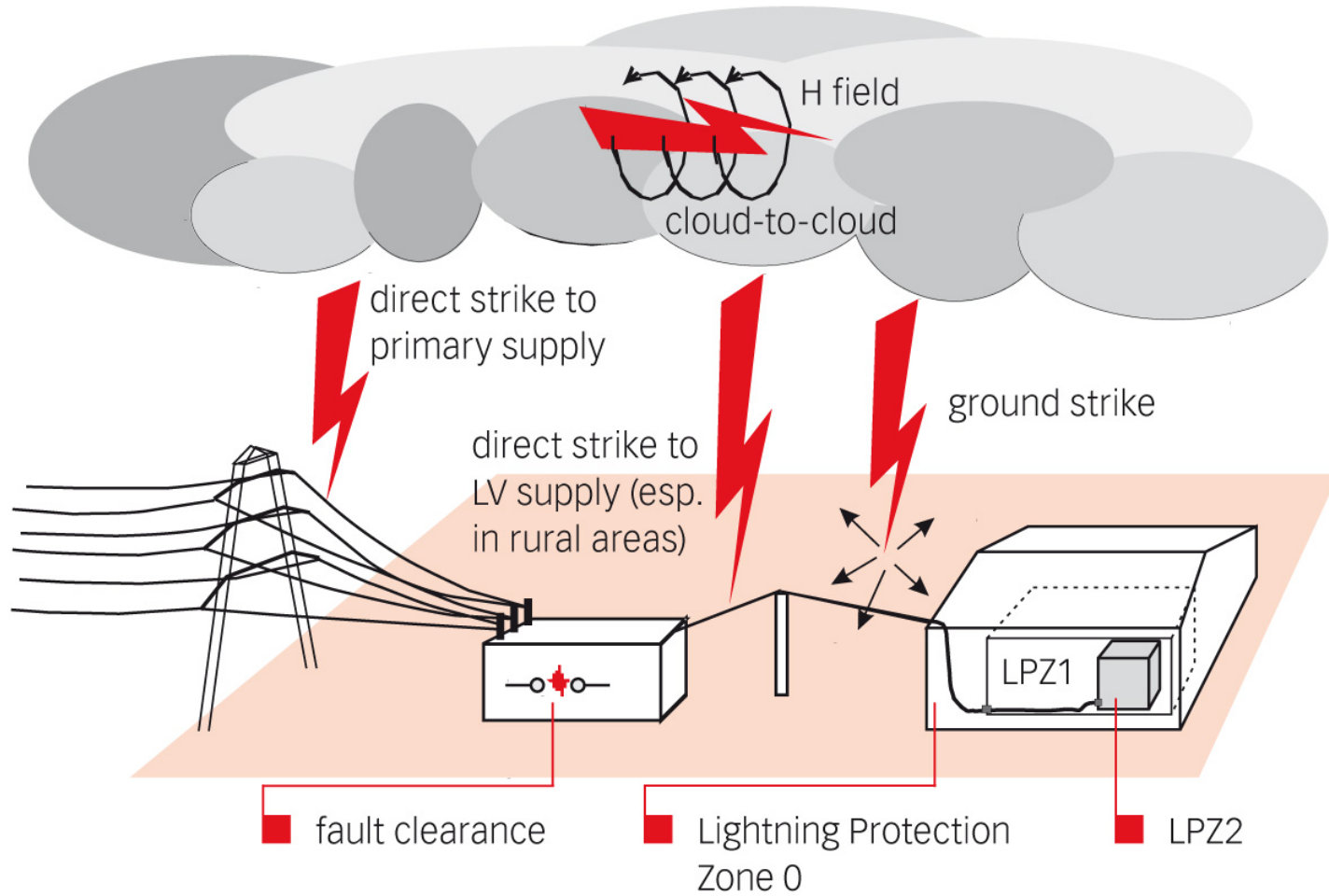


**High energy transients → Effect of lightning strokes or switching of major power systems like capacitor bank switching.**



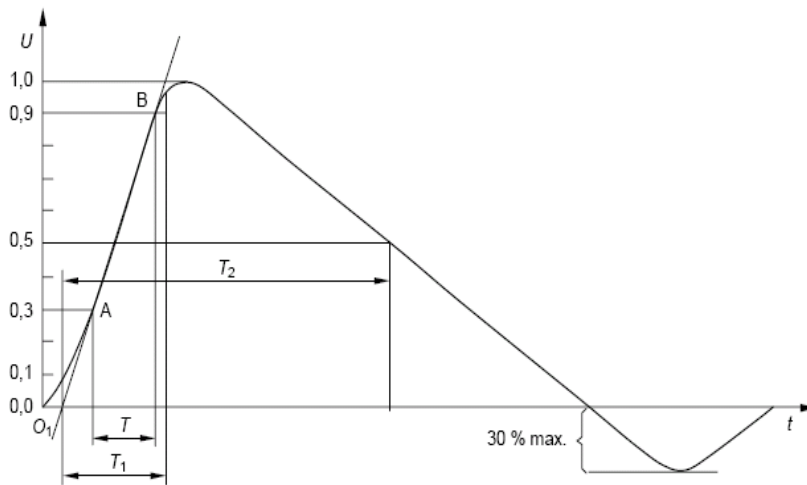
$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Lightning strokes



$$s(q_k) = \sqrt[n]{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$

# Standardized pulse



High energy pulse  
with low bandwidth: < 100 kHz

1,2/50 us      8/20us

Voltage amplitude up to 4 kV

Current amplitude up to 2 kA



$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$



- Trends for next revision of IEC 61000-4-5

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

## Maintenance of IEC 61000-4-5



- Started Dec 2010
- Result inquiry within MT12 and observations from national committees defined the program.

### No change of:

- Test levels
- Generator specifications
- Phase angle spec
- Separation of 10/700 with 1.2/50 pulse

### Change (review) of:

- Add mathematical formula for wave shape
- Harmonization of CDN up to 200 A
- Specify High Speed dataline CDN
- Phase synchronization in 3 phase systems
- New calibration table for 10 Ohm
- Test setup for class II equipment
- Test setup for shielded control lines
- Harmonization with ITU-T.K series
- Clear statement about 2 methods 60060-1, 60469-1
- Development of MU (annex D)

$$s(q_k) = \sqrt[n]{\frac{1}{n-1}}$$



■ Numerical model

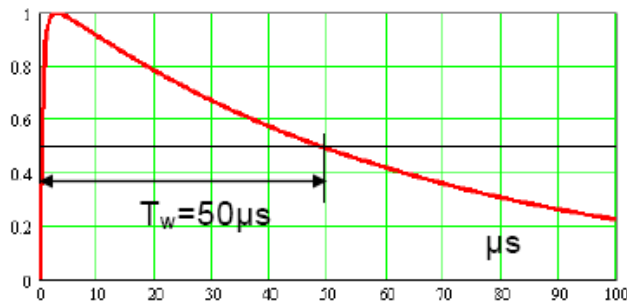


Figure E. 1: Voltage surge (1,2/50μs): Late time response

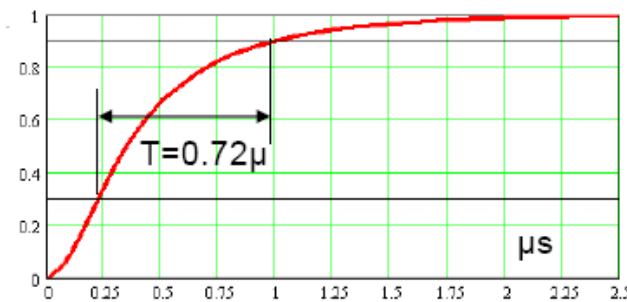


Figure E. 2: Voltage surge (1,2/50μs): Early time response

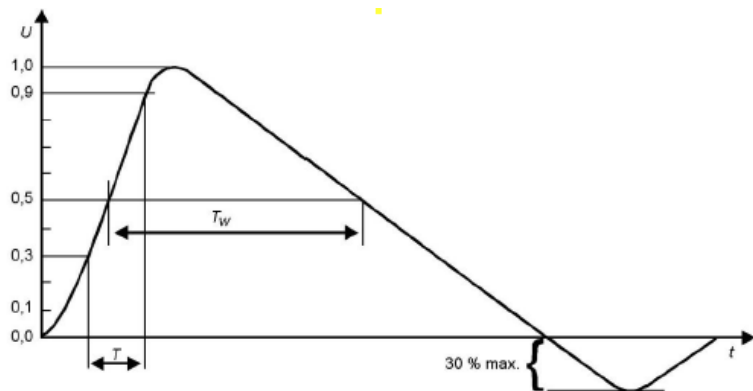
$$V_{SURGE} t = k_V \cdot \left[ \frac{V}{k_{SURGE}} \cdot \frac{\left(\frac{t}{\tau}\right)^{n_{SURGE}}}{1 + \left(\frac{t}{\tau}\right)^{n_{SURGE}}} \cdot e^{-\frac{t}{\tau}} \right]$$

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

# Maintenance of IEC 61000-4-5



## ■ Only one calibration method

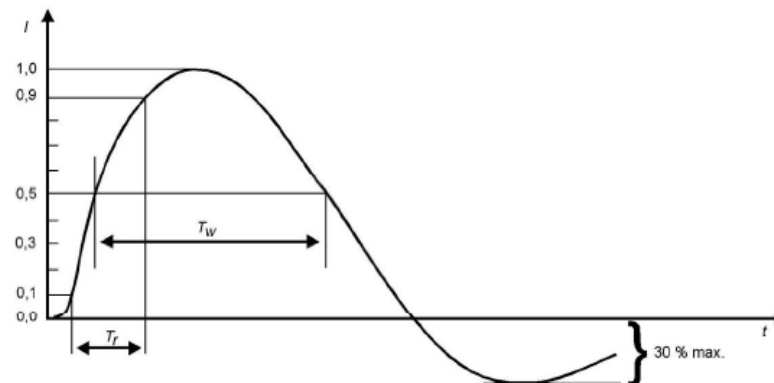


Front time:  $T_f = 1,67 \times T = 1,2 \mu\text{s} \pm 30\%$   
 Duration:  $T_d = T_w = 50 \mu\text{s} \pm 20\%$

NOTE 1 The open circuit voltage waveform at the output of the coupling/decoupling network may have a considerable undershoot, in principle as the curve shown in this figure.

NOTE 2 The value 1,67 is the reciprocal of the difference between the 0,9 and 0,3 thresholds.

Figure 2 – Waveform of open-circuit voltage (1,2/50 μs) at the output of the generator with no CDN connected



Front time:  $T_f = 1,25 \times T_r = 8 \mu\text{s} \pm 20\%$   
 Duration:  $T_d = 1,18 \times T_w = 20 \mu\text{s} \pm 20\%$

NOTE 1 The 30 % undershoot specification applies only at the generator output. At the output of the coupling/decoupling network there is no limitation on undershoot or overshoot.

NOTE 2 The value 1,25 is the reciprocal of the difference between the 0,9 and 0,1 thresholds.

NOTE 3 The value 1,18 is derived from empirical data.

Figure 3 – Waveform of short-circuit current (8/20 μs) at the output of the generator

Table 2 – Definitions of the waveform parameters 1,2/50 μs – 8/20 μs

|                       | Front time $T_f$<br>μs | Duration $T_d$<br>μs |
|-----------------------|------------------------|----------------------|
| Open-circuit voltage  | 1,2 ± 30 %             | 50 ± 20 %            |
| Short-circuit current | 8 ± 20 %               | 20 ± 20 %            |

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

# Maintenance of IEC 61000-4-5



- CDN specification up to 200 A

**Table 4 – Voltage waveform specification at the EUT port of the a.c./d.c mains supply CDN**

| Surge voltage parameters under open-circuit conditions <sup>a</sup>  | Coupling impedance      |                          |
|--|-------------------------|--------------------------|
|  | 18 μF                   | 9 μF + 10 Ω              |
| Peak voltage   |                         |                          |
| Current rating ≤ 16 A  | Set voltage +10 %/-10 % | Set voltage +10 %/-10 %  |
| 16 A < Current rating ≤ 32 A   | Set voltage +10 %/-10 % | Set voltage +10 %/-10 %  |
| 32 A < Current rating ≤ 63 A   | Set voltage +10 %/-10 % | Set voltage +10 %/-15 %  |
| 63 A < Current rating ≤ 125 A  | Set voltage +10 %/-10 % | Set voltage +10 %/- 20 % |
| 125 A < Current rating ≤ 200 A   | Set voltage +10 %/-10 % | Set voltage +10 %/- 25 % |
| Front time   | 1,2 μs ± 30 %           | 1,2 μs ± 30 %            |
| Duration   |                         |                          |
| Current rating ≤ 16 A  | 50 μs +10 μs/-10 μs     | 50 μs +10 μs/-25 μs      |
| 16 A < Current rating ≤ 32 A   | 50 μs +10 μs/-15 μs     | 50 μs +10 μs/-30 μs      |
| 32 A < Current rating ≤ 63 A   | 50 μs +10 μs/-20 μs     | 50 μs +10 μs/-35 μs      |
| 63 A < Current rating ≤ 125 A  | 50 μs +10 μs/-25 μs     | 50 μs +10 μs/-40 μs      |
| 125 A < Current rating ≤ 200 A   | 50 μs +10 μs/-30 μs     | 50 μs +10 μs/-45 μs      |
| <sup>a</sup> The measurement of the surge voltage parameters shall be done with the a.c./d.c. mains supply port of the CDN open-circuit. |                         |                          |

NOTE 1 The current rating is related to the CDN and not related to the rating of an EUT.

- Technical background published in TESEQ newsletter 02/2009: Pulse integrity vs. Voltage drop

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

## Maintenance of IEC 61000-4-5



- Surge coupling on datalines
- Clear split between indoor and outdoor lines
- 10/700 pulse applies only to outdoor lines, so it has been moved to an annex

### **Annex A** (normative)

**Surge testing for unshielded outdoor symmetrical communication lines  
intended to interconnect to widely dispersed systems**

## **A.2 10/700 $\mu$ s combination wave generator**



$$s(q_k) = \sqrt{\frac{1}{n-1}}$$

## Maintenance of IEC 61000-4-5



- Existing specifications dates from times where high speed data transfer was 150 kHz... now up to 10Gbit/s for Ethernet
- Section about dataline coupling has been reviewed
- Calibration specification for dataline CDNs
- Harmonisation with specification from ITU-T.K series and several other telecom standards

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - \bar{q})^2}$$

## Maintenance of IEC 61000-4-5



- IEC 61000-4-5 Ed 3.0
- Publication earliest end 2013

$$s(q_k) = \sqrt{\frac{1}{n-1} \sum_{k=1}^n (q_k - Q)^2}$$



Thank you for your attention.



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